


[DOWNLOAD](#)


Electrical Overstress (EOS): Devices, Circuits and Systems (Hardback)

By Steven H. Voldman

John Wiley Sons Inc, United States, 2013. Hardback. Condition: New. 1. Auflage. Language: English . Brand New Book. Electrical Overstress (EOS) continues to impact semiconductor manufacturing, semiconductor components and systems as technologies scale from micro- to nano-electronics. This book teaches the fundamentals of electrical overstress and how to minimize and mitigate EOS failures. The text provides a clear picture of EOS phenomena, EOS origins, EOS sources, EOS physics, EOS failure mechanisms, and EOS on-chip and system design. It provides an illuminating insight into the sources of EOS in manufacturing, integration of on-chip, and system level EOS protection networks, followed by examples in specific technologies, circuits, and chips. The book is unique in covering the EOS manufacturing issues from on-chip design and electronic design automation to factory-level EOS program management in today's modern world. Look inside for extensive coverage on: * Fundamentals of electrical overstress, from EOS physics, EOS time scales, safe operating area (SOA), to physical models for EOS phenomena * EOS sources in today's semiconductor manufacturing environment, and EOS program management, handling and EOS auditing processing to avoid EOS failures * EOS failures in both semiconductor devices, circuits and system * Discussion of how to distinguish between EOS...



[READ ONLINE](#)

[6.84 MB]

Reviews

This ebook is indeed gripping and fascinating. it had been writtern really properly and helpful. I am very easily could possibly get a satisfaction of reading a published publication.

-- **Maude Ritchie**

The publication is great and fantastic. It can be filled with knowledge and wisdom You wont truly feel monotony at at any moment of your time (that's what catalogues are for about if you ask me).

-- **Dr. Marcos Grimes III**